

<b>Notice of References Cited</b>	Application/Control No. 10/043,637	Applicant(s)/Patent Under Reexamination KHU ET AL.	
	Examiner XUAN M. THAI	Art Unit 2111	Page 1 of 1

#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-5,689,516	11-1997	Mack et al.	714/725
	B	US-5,706,297	01-1998	Jeppesen et al.	714/30
	C	US-5,708,773	01-1998	Jeppesen et al.	714/30
	D	US-6,112,298	08-2000	Deao et al.	712/227
	E	US-6,243,842	06-2001	Slezak et al.	714/724
	F	US-6,266,801	07-2001	Jin, London	716/8
	G	US-6,421,812	07-2002	Wang et al.	716/5
	H	US-6,430,719	08-2002	Slezak et al.	714/734
	I	US-6,732,311	05-2004	Fischer et al.	714/737
	J	US-6,324,096	11-2001	Tomita, Shozo	365/185.05
	K	US-6,757,844	06-2004	Lulla et al.	714/30
	L	US-			
	M	US-			

#### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)			
	U	Narayanan et al., "Reconfigurable Scan Chains: A Novel Approach to Reduce Test Application Time", IEEE, 1993, pages 710-715.			
	V	Robinson, Gordon D. "Why 1149.1 (JTAG) Really Works", Electro/94 International. Conference Proceedings Combined Volumes, 10-12 May 1994, pages 749-754.			
	W	"Boundary Scan Descriptive Language for Non-JTAG Components" IBMTDB, October 1993, vol. 36, issue no. 10, pages 599-600.			
	X				

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.